

April 2000

# **FQA7N60**

# **600V N-Channel MOSFET**

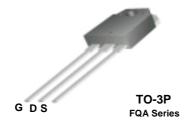
## **General Description**

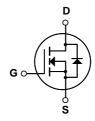
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supply.

#### **Features**

- 7.7A, 600V,  $R_{DS(on)} = 1.0\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 29 nC)
- Low Crss (typical 16 pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





# **Absolute Maximum Ratings** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter		FQA7N60	Units	
V <sub>DSS</sub>	Drain-Source Voltage		600	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C) - Continuous (T <sub>C</sub> = 100°C)		7.7	А	
			4.8	А	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	30.8	А	
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	580	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	7.7	А	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	15.2	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns	
$P_{D}$	Power Dissipation (T <sub>C</sub> = 25°C)		152	W	
	- Derate above 25°C		1.22	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

# **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.82	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	3	Min	Тур	Max	Units
Off Cha	aracteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		600			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced	to 25°C		0.67		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V				10	μΑ
		V <sub>DS</sub> = 480 V, T <sub>C</sub> = 125°C				100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V				-100	nA
On Cha	aracteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$		3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 3.9 \text{ A}$			0.8	1.0	Ω
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 50 \text{ V}, I_{D} = 3.9 \text{ A}$	(Note 4)		6.5		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0  MHz			1100 135 16	1430 175 21	pF pF pF
	-				16	21	p⊦
Switch	ing Characteristics	T				T	1
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 300 \text{ V}, I_D = 7.4 \text{ A},$			30	70	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$			80	170	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		(NI-1- 4.5)		65	140	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4, 5)		60	130	ns
Qg	Total Gate Charge	$V_{DS} = 480 \text{ V}, I_{D} = 7.4 \text{ A},$			29	38	nC
$Q_{gs}$	Gate-Source Charge	V <sub>GS</sub> = 10 V			7		nC
Q <sub>gd</sub>	Gate-Drain Charge		(Note 4, 5)		14.5		nC
	Source Diode Characteristics a	nd Maximum Rating	S				
Drain-S		Maximum Continuous Drain-Source Diode Forward Current				7.7	Α
		ode Forward Current				1.1	
I <sub>S</sub>						30.8	A
I <sub>S</sub>	Maximum Continuous Drain-Source Dic						
Drain-S I <sub>S</sub> I <sub>SM</sub> V <sub>SD</sub> t <sub>rr</sub>	Maximum Continuous Drain-Source Did Maximum Pulsed Drain-Source Diode F	orward Current				30.8	Α

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 18mH, I<sub>AS</sub> = 7.7A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub> ≤ 7.4A, di/dt ≤ 200A/µs, V<sub>DD</sub> ≤ BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

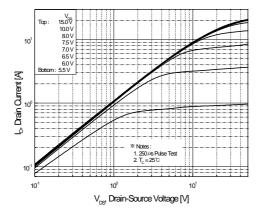


Figure 1. On-Region Characteristics

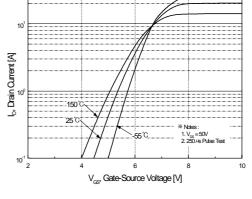


Figure 2. Transfer Characteristics

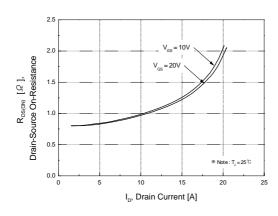


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

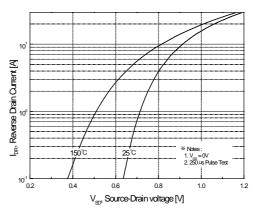


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

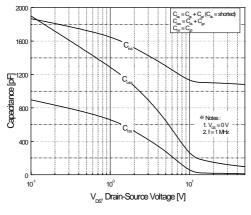


Figure 5. Capacitance Characteristics

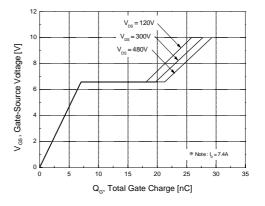


Figure 6. Gate Charge Characteristics

# Typical Characteristics (Continued)

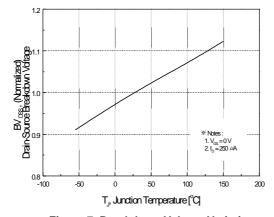


Figure 7. Breakdown Voltage Variation vs. Temperature

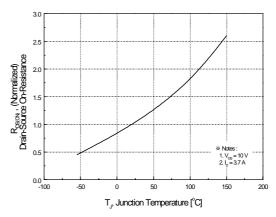


Figure 8. On-Resistance Variation vs. Temperature

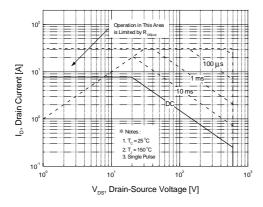


Figure 9. Maximum Safe Operating Area

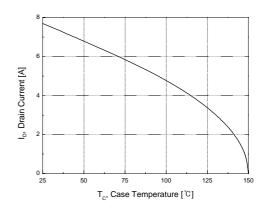


Figure 10. Maximum Drain Current vs. Case Temperature

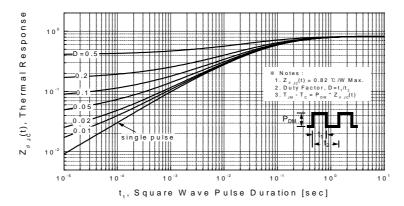
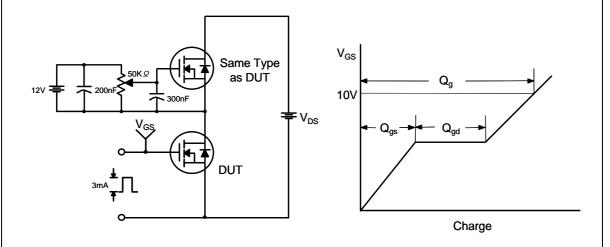


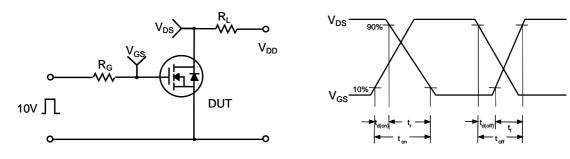
Figure 11. Transient Thermal Response Curve

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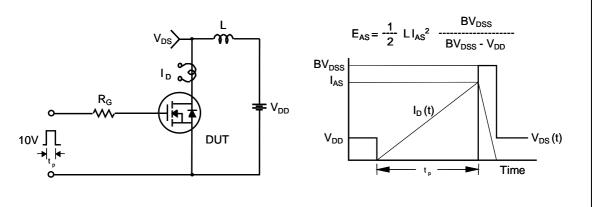
## **Gate Charge Test Circuit & Waveform**



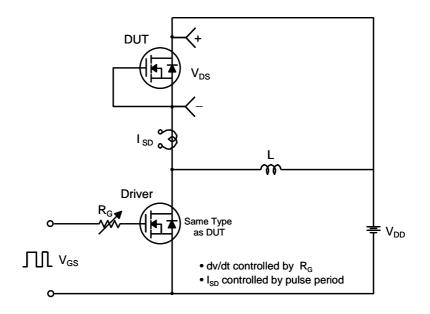
# **Resistive Switching Test Circuit & Waveforms**

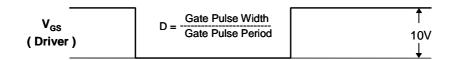


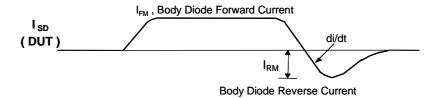
# **Unclamped Inductive Switching Test Circuit & Waveforms**

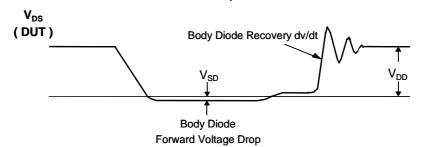


## Peak Diode Recovery dv/dt Test Circuit & Waveforms

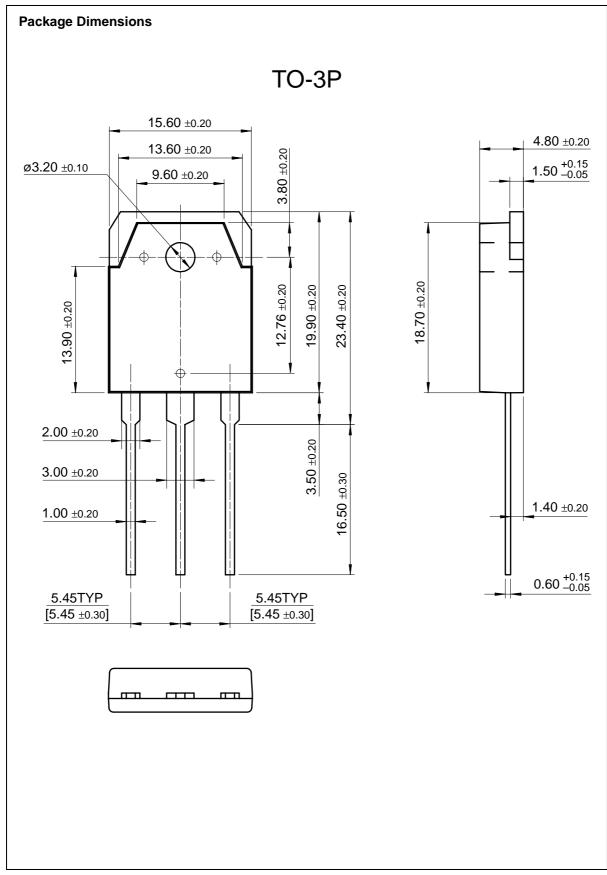








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